
***In situ* Laser interferometric holoellipsometry with normal and brewster reflections of light**

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This paper presents in situ holoellipsometry using a laser interferometric holoellipsometer with binary modulation of the polarization and of the both normal and Brewster reflection of polarized light from an optical uniaxial bi-dimensional crystal posted in the arm of Michelson interferometer, which is used as a technical basis for the device.

Keywords: *ellipsometry, Michelson interferometer, binary modulation of polarization, uniaxial bi-dimensional crystal.*

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